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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Shunji MAEDA et al.

Serial No.: 09/294,137

Filed: April 20, 1999

For: DEFECT INSPECTION METHOD AND APPARATUS

Group: 2621

Examiner: Brian P. Werner

RECEIVED

OCT 30 2003

Technology Center 2600

AMENDMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

October 29, 2003

Sir:

In response to the Notice of Non-Compliant Amendment (Paper No. 23) dated on October 23, 2003, and in response to the Office Action (Paper No. 20) dated on May 12, 2003, please amend the above-identified application as follows.

Amendments to the Claims begin on page 2 of this paper.

Remarks/Arguments begin on page 13 of this paper.